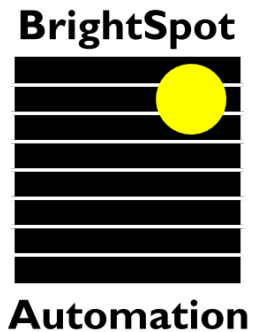


ContactSpot



Measure:

- **Contact Resistivity**
- **Semiconductor Sheet Resistance**
- **Line Resistance**
- **Conductive Adhesives**

Optimize cell performance

R&D experiments

Factory quality control

Accurate values for grid modeling

Metal gridline measurement

Contact resistivity to silicon ($m\Omega\text{-cm}^2$)

Line resistance ($m\Omega/\text{cm}$)

Sheet resistance between gridlines (Ω/square)

< 30 sec/test including sample loading & alignment

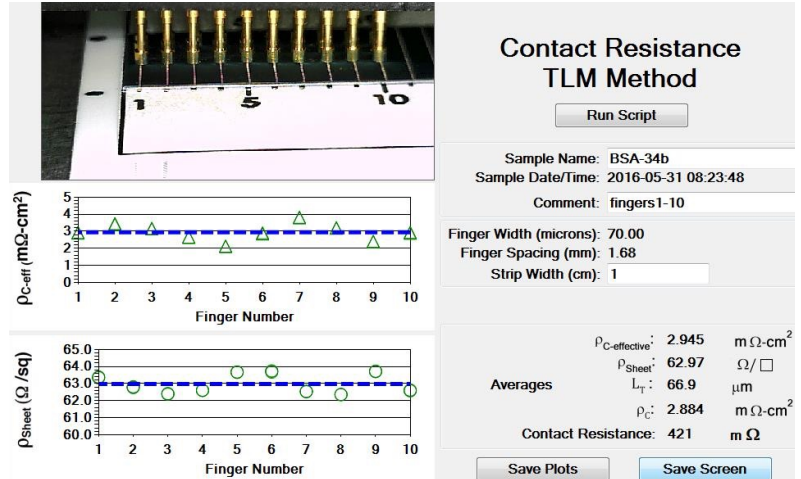
10 current injection and 10 voltage measurement probes

Microscope with screen display and x-theta adjustment for fast sample alignment

Correction factors for voltage drop down narrow fingers

Options:

- 4-point probe head for sheet and bulk resistivity measurement. Probes spaced 1.27mm apart.
- Calibrated probe head



Benefits over manual contact resistivity measurements

Much faster test time

More consistent results

No room-light artifacts

Mapping across the test strip

Automated data analysis

Advanced algorithms

